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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/084,148	02/28/2002	Tatsuya Ohguro	220199US2S	4941	
22850	7590 02/09/2004		EXAM	INER	
OBLON, SP	IVAK, MCCLELLAN	FARAHANI, DANA			
	1940 DUKE STREET ALEXANDRIA, VA 22314		ART UNIT	PAPER NUMBER	
ALEXANDR	IA, VA 22314		2814		
				DATE MAILED 02/00/2004	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)			
Office Action Summan.	10/084,148	OHGURO, TATSUYA			
Office Action Summary	Examiner	Art Unit			
The MANUALO DATE of this communication are	Dana Farahani	2814			
Th MAILING DATE of this communication app Period for Reply	bears on the cover shiet with the C	correspondence address			
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION.  - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication.  - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period v - Failure to reply within the set or extended period for reply will, by statute - Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).  Status	36(a). In no event, however, may a reply be tir y within the statutory minimum of thirty (30) day vill apply and will expire SIX (6) MONTHS from , cause the application to become ABANDONE	nely filed  rs will be considered timely. I the mailing date of this communication. ED (35 U.S.C. § 133).			
1) Responsive to communication(s) filed on 19 D	<u>ecember 2003</u> .				
2a)⊠ This action is <b>FINAL</b> . 2b)□ This	☐ This action is FINAL. 2b) ☐ This action is non-final.				
Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims					
Claim(s) 1.4-7.10-13 and 15-25 is/are pending in the application.  4a) Of the above claim(s) is/are withdrawn from consideration.  Claim(s) 16-19 is/are allowed.  Claim(s) 1,4-7,10-13,15 and 22 is/are rejected.  Claim(s) 20,21 and 23-25 is/are objected to.  Claim(s) are subject to restriction and/or election requirement.					
Application Papers					
9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) access applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Examine	epted or b) objected to by the drawing(s) be held in abeyance. Se ion is required if the drawing(s) is ob	e 37 CFR 1.85(a). jected to. See 37 CFR 1.121(d).			
Priority under 35 U.S.C. §§ 119 and 120					
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the priority application from the International Bureau * See the attached detailed Office action for a list 13) Acknowledgment is made of a claim for domestic since a specific reference was included in the first 37 CFR 1.78.  a) The translation of the foreign language pro 14) Acknowledgment is made of a claim for domestic reference was included in the first sentence of the	s have been received. s have been received in Application in the comments have been received in Application (PCT Rule 17.2(a)). of the certified copies not received priority under 35 U.S.C. § 119(ast sentence of the specification of the control of the specification application has been received to the specification of the specification of the specification application has been received to the specification of the specification of the specification application has been received to the specification of the specification of the specification application has been received to the specification of the specification o	ion No ed in this National Stage ed. e) (to a provisional application) r in an Application Data Sheet. eeived. and/or 121 since a specific			
Attachment(s)	,				
<ol> <li>Notice of References Cited (PTO-892)</li> <li>Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>Information Disclosure Statement(s) (PTO-1449) Paper No(s)</li></ol>	5) Notice of Informal F	(PTO-413) Paper No(s) Patent Application (PTO-152)			

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#### **DETAILED ACTION**

## Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
  - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1, 4-6, 13 and 22 are rejected under 35 U.S.C. 103(a) as being unpatentable over Nowak et al., hereinafter Nowak (US Patent 6,191,451), newly cited.

Regarding claims 1, 4, and 22, a semiconductor device comprising a semiconductor substrate 150; a first conductivity type well area 130 formed in a surface area of the semiconductor substrate; a plurality of element isolation areas 20 formed in the well area; a second conductivity type semiconductor layer 136 formed at a first area of the well area which is isolated by the element isolation areas, the second conductivity type semiconductor layer configuring a first electrode of a capacitor; a first conductivity type semiconductor layer 138 formed in a second area of the well area which is isolated by the element isolation areas, the first conductivity type semiconductor layer configuring: a second electrode of the capacitor; and a first conductivity type low resistance area 140 provided at a base portion of the well area, the low resistance area having a resistive value lower than that of the well area, wherein the low resistance area is not in contact with a depletion layer of a junction portion between the second conductivity type semiconductor layer and the well area, and is not in contact with a depletion layer of a junction portion between the first conductivity type semiconductor

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layer and the well area. Although, Nowak does not disclose the well is in contact with the element isolation areas, it would have been obvious to one of ordinary skill in the art at the time of the invention to modify the length of the isolation regions, since such a modification would have involved a mere change in size. A change in size is generally recognized as being within the level of ordinary skill in the art. *In re Rose, 105 USPQ* 237 (CCPA 1955).

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Regarding claims 5 and 6, Nowak renders obvious the claimed invention except for the impurity concentration of the low resistance area. It would have been obvious to one of ordinary skill in the art at the time the invention was made to include these values, since it has been held that discovering an optimum value of a result effective variable involves only routine skill in the art. *In re Boesch*, 617 F.2d 272, 205 USPQ 215 (CCPA 1980).

Regarding claim 13, note that Nowak discloses the limitation in the claim, as discussed above, further disclosing a second well area 134; a second conductivity type base layer 142 of a bipolar transistor (comprising regions 134 and 144, 130 and 142, 132 and 136) formed on the first well; and a first conductivity type second electrode 136 on the base layer.

3. Claims 7, 10-12 and 15 are rejected under 35 U.S.C. 103(a) as being unpatentable over Nowak as applied to claim 1 above, and further in view of Stolmeijer et al., hereinafter Stolmeijer (U.S. 5,742,090), previously cited.

Regarding claims 7, 10, and 15, Nowak discloses the limitations in the claims, as discussed above, further disclosing a second well 134. Nowak does not disclose a MOS transistor.

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Stolmeijer discloses in figure 5 a MOS transistor 20 in an integrated circuit.

Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention to include a MOS transistor in Nowak's structure in order to make an integrated circuit application which employs both capacitors and MOS transistors (note that in claim 15 a first conductivity type semiconductor layer is one of a source/drain regions of the transistor).

Regarding claims 11 and 12, Nowak in view Stolmeijer renders obvious the claimed invention except for the impurity concentration of the low resistance area. It would have been obvious to one of ordinary skill in the art at the time the invention was made to include these values, since it has been held that discovering an optimum value of a result effective variable involves only routine skill in the art. *In re Boesch*, 617 F.2d 272, 205 USPQ 215 (CCPA 1980).

#### Allowable Subject Matter

- 4. Claims 16-19 are allowed.
- 5. The following is a statement of reasons for the indication of allowable subject matter:

The reason for indication of allowability of claims 16-19 is inclusion therein of the limitations that of the circuitry stated in those claims.

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6. Claims 20, 21, and 23-25 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

7. The following is a statement of reasons for the indication of allowable subject matter: the primary reason for indication of allowability of claims 20, 21, and 23-25 is inclusion therein of the limitations of the third layer and the second low resistance areas.

### Response to Arguments

8. Applicant's arguments with respect to the previously rejected claims have been considered but are most in view of the new grounds of rejection.

#### Conclusion

9. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of

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the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Dana Farahani whose telephone number is (571)272-1706. The examiner can normally be reached on M-F 9:00AM - 6:00PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael M Fahmy can be reached on (571)272-1705. The fax phone number for the organization where this application or proceeding is assigned is (703) 872-9306.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703)308-0956.

D. Farahani

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